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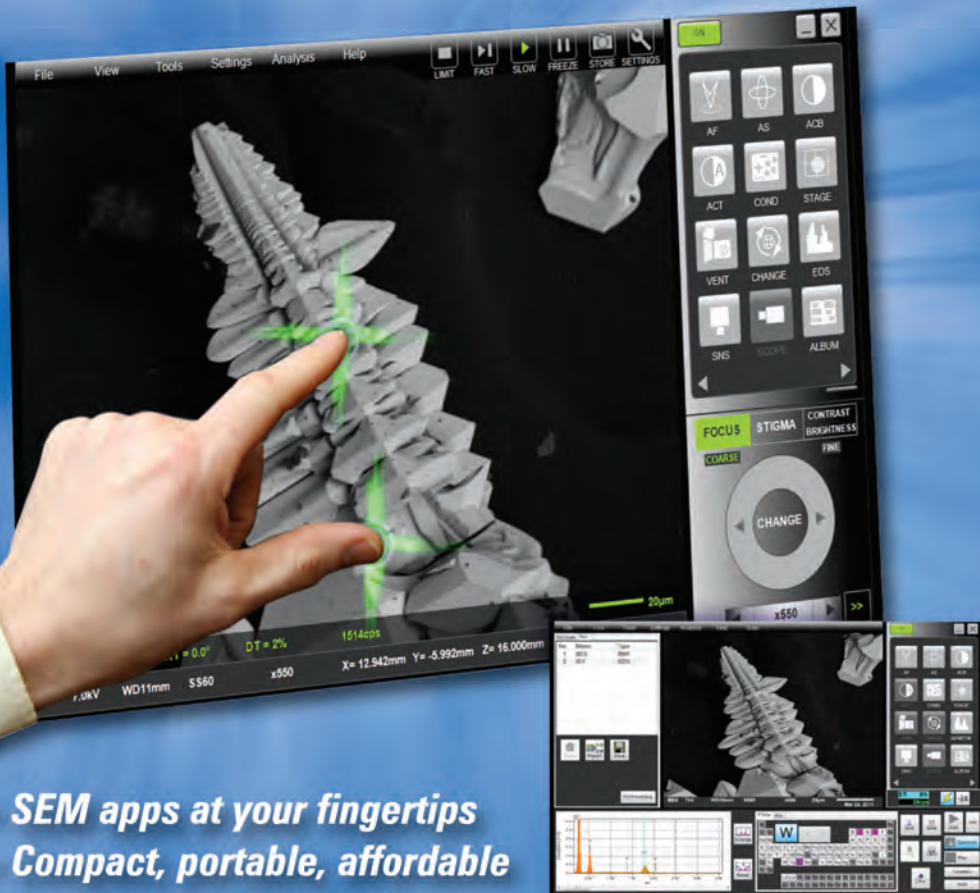
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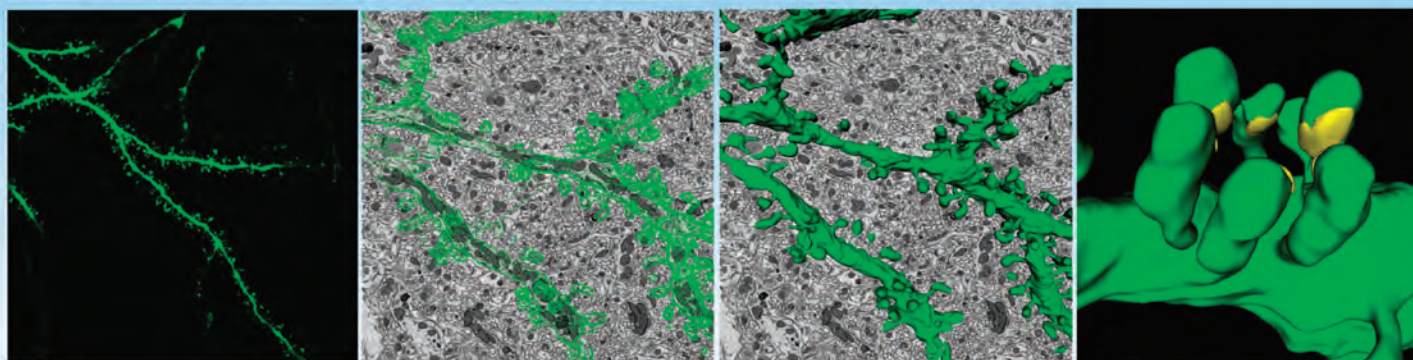
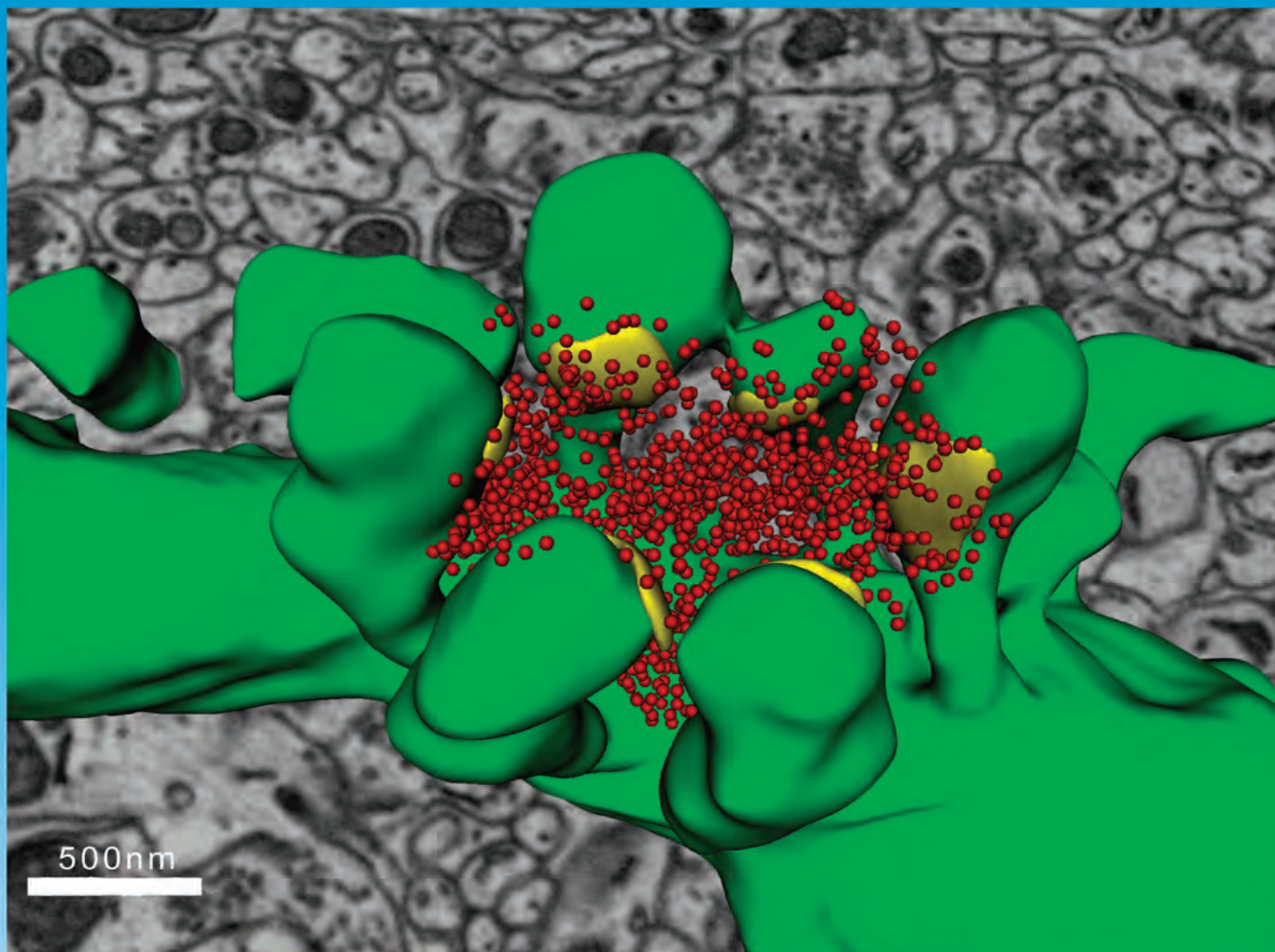
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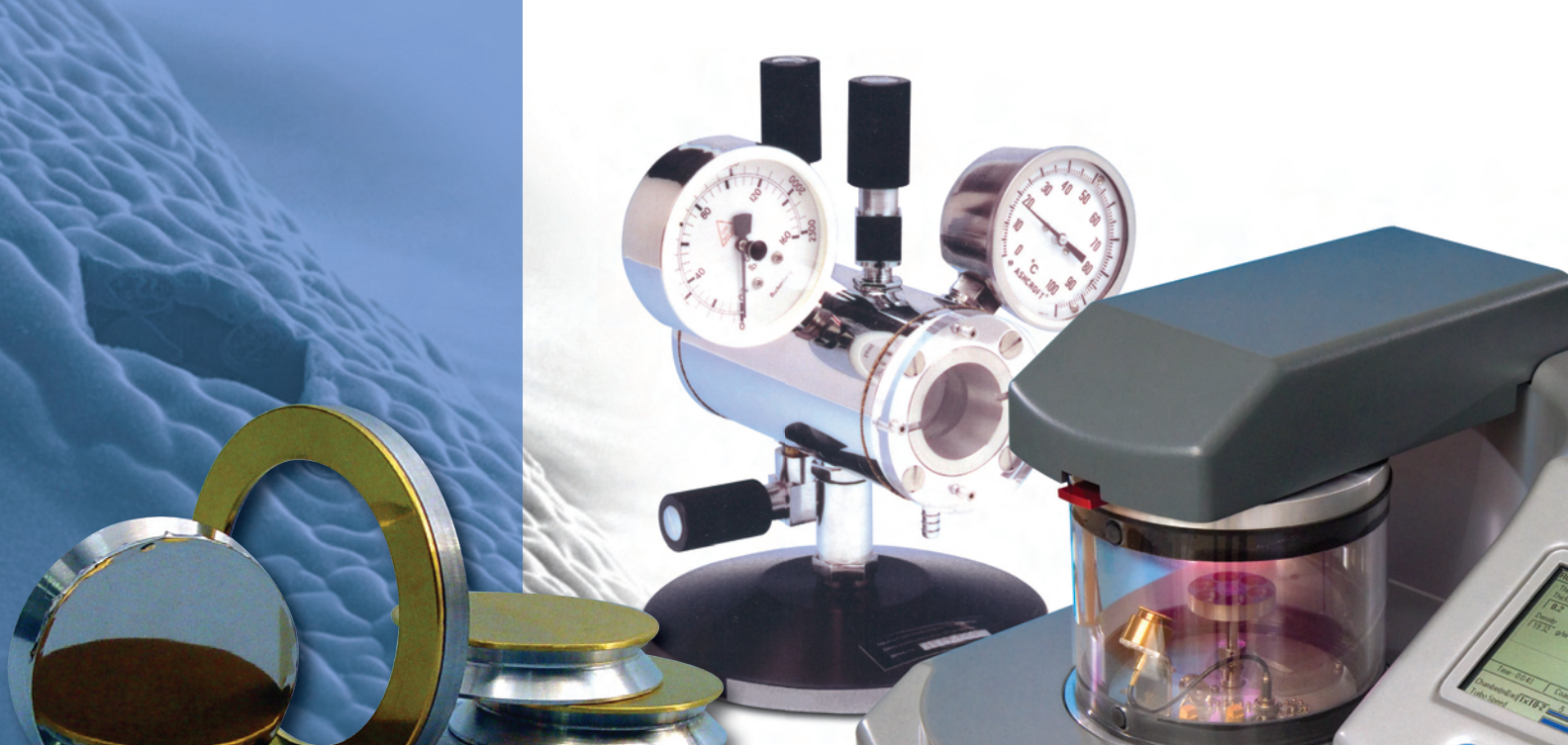


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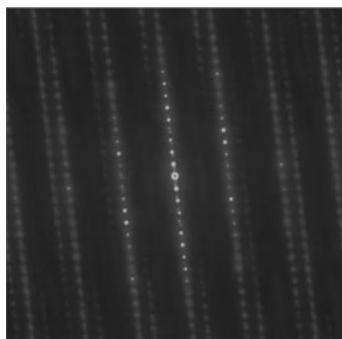
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On the Cover: Electron diffraction pattern of aspirin. For further information see Jiang et al., pages 879–885.

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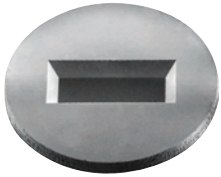
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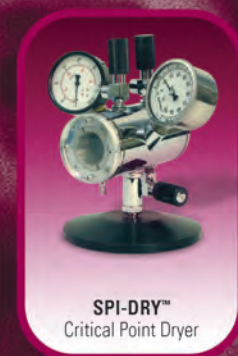
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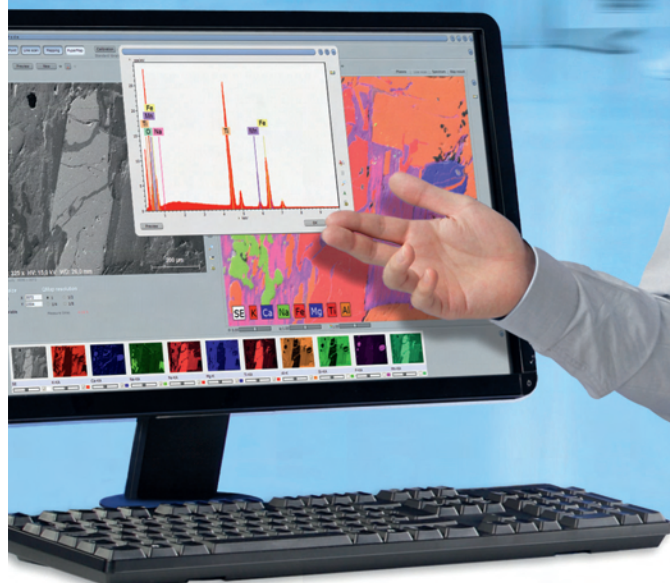
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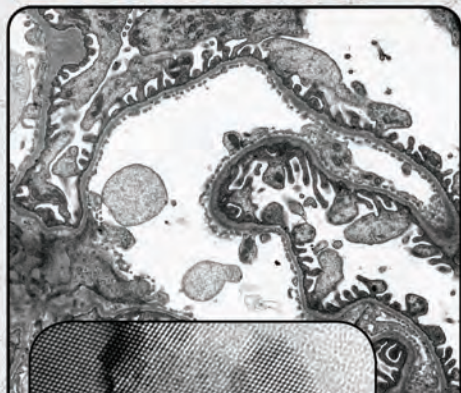


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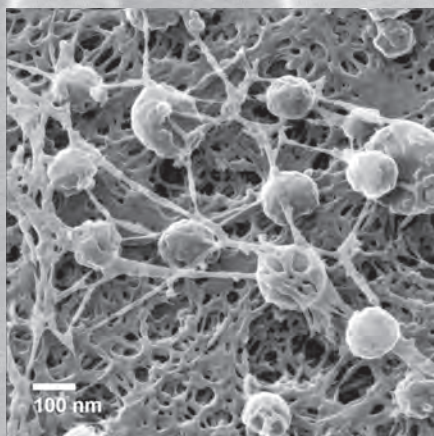
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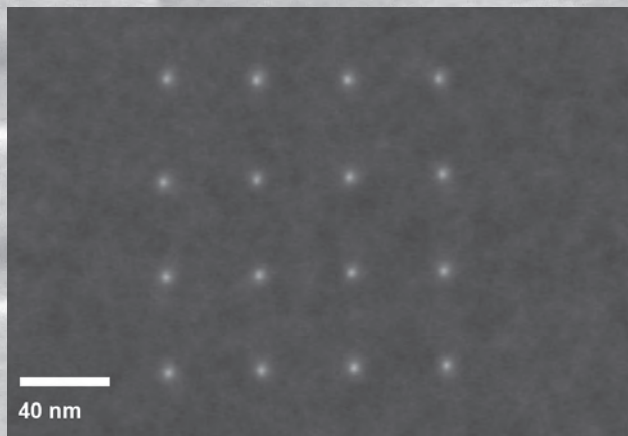
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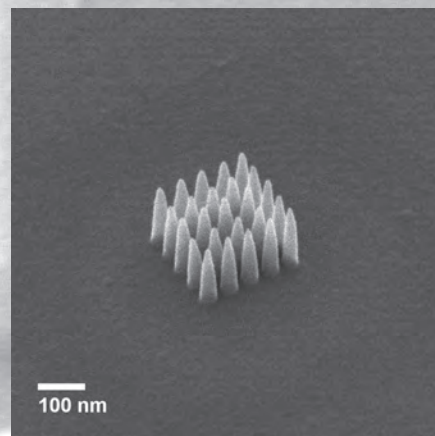
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High-resolution image of an uncoated biological sample showing virus particles attached to a cell.



Array of 5 (± 1) nm nanopores in Si_3N_4 membrane. A 10×10 array can be created in under one minute.



Array of Pt nano-pillars (35 nm diameter & 50 nm pitch) deposited using the helium ion beam.

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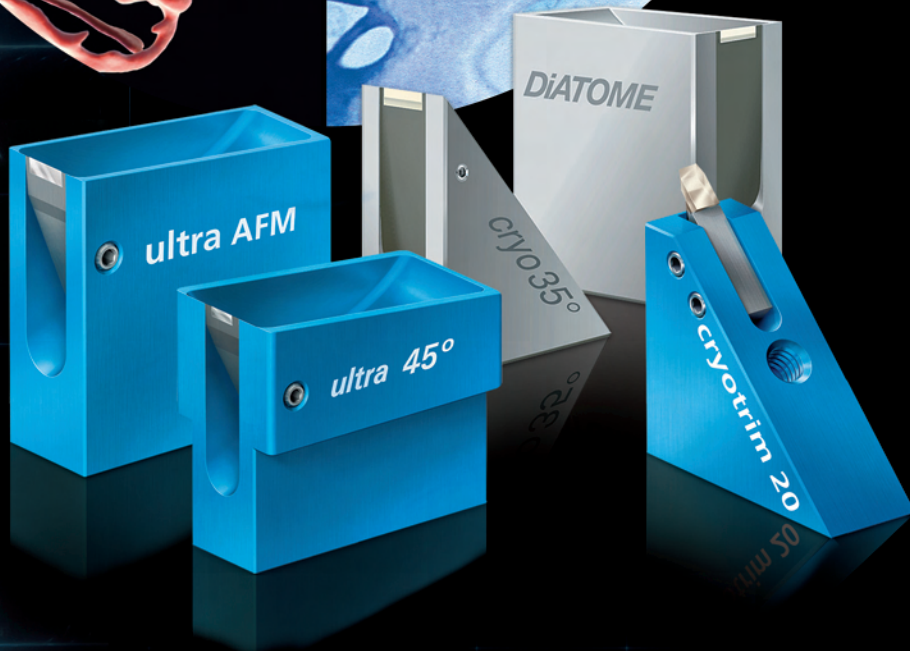
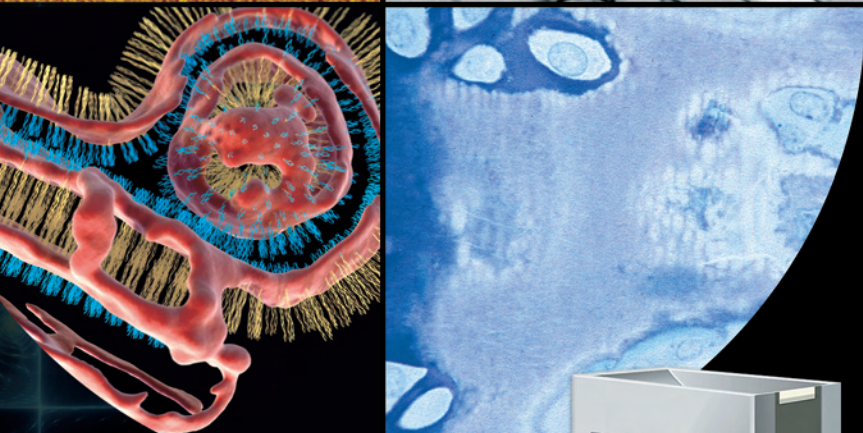
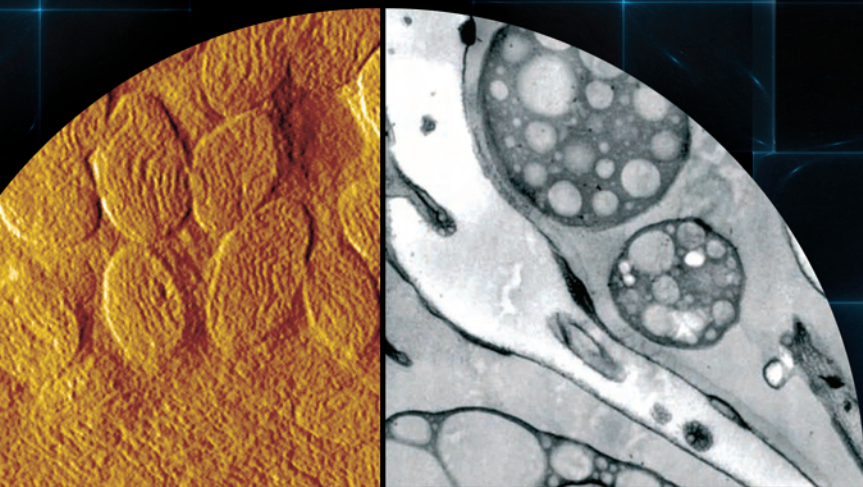


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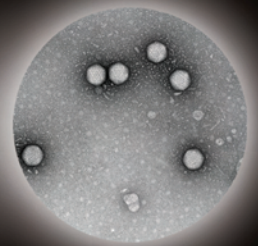
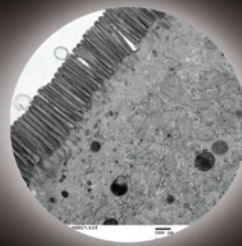
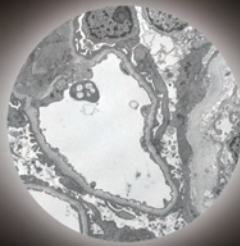
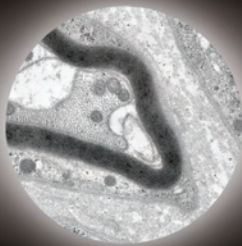
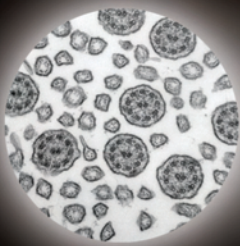
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